

●General Description

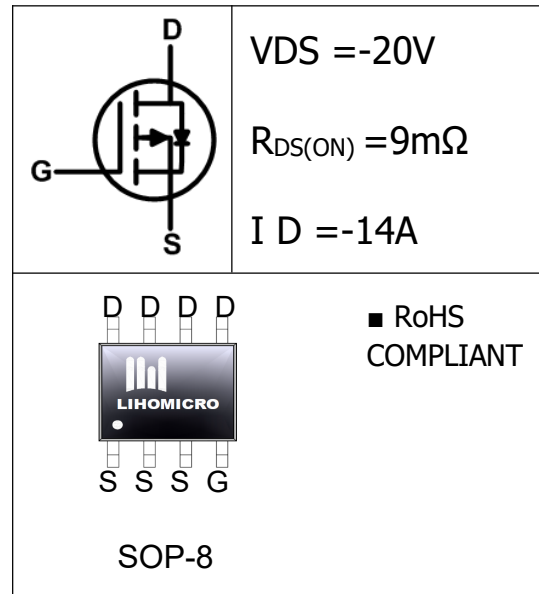
The LH09P02 uses trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. This device is suitable for high current load applications.

●Features

- Advance high cell density Trench technology
- Low $R_{DS(ON)}$ to minimize conductive loss
- Low Gate Charge for fast switching

●Application

- LED/LCD/PDP TV and monitor Lighting
- Power Supplies


●Ordering Information:

Part Number	LH09P02
Package	SOP-8
Basic Ordering Unit (pcs)	4000
Normal Package Material Ordering Code	LH09P02S-SOP8-TAP
Halogen Free Ordering Code	LH09P02S-SOP8TAP-HF

●Absolute Maximum Ratings (TC =25°C)

PARAMETER	SYMBOL	Value	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	-20	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current , $T_C = 25^\circ C$	I_D	-14	A
Pulsed drain current ($T_C = 25^\circ C$, t_p limited by T_{jmax}) ¹	I_{DM}	-55	A
Single Pulse Avalanche Energy	E_{AS}	90	mJ
Power Dissipation($T_C=25^\circ C$)	P_D	36	W
Operating Temperature	T_J	-55~+150	°C
Storage Temperature	T_{STG}	-55~+150	°C

●Electronic Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	-20	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	-0.3	--	-1.0	V
Drain-source On Resistance ²	$R_{DS(ON)}$	$V_{GS}=-10V, I_D=-8A$	--	9	13	mΩ
		$V_{GS}=-4.5V, I_D=-7A$	--	10	15	
		$V_{GS}=-2.5V, I_D=-5A$	--	13	18	
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=-20V, V_{GS}=0V, T_J=25^\circ C$	--	--	-1	μA
		$V_{DS}=-20V, V_{GS}=0V, T_J=125^\circ C$	--	--	-100	μA
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 12V, V_{DS}=0V$	--	--	±100	nA
Gate Resistance	R_g	$F=1MHz$	--	2.3	--	Ω
Input Capacitance	C_{iss}	$V_{GS}=0V,$ $V_{DS}=-10V$ $f=1.0MHz$	--	4600	--	pF
Output Capacitance	C_{oss}		--	500	--	
Reverse transfer Capacitance	C_{rss}		--	420	--	
Total Gate Charge	Q_g	$I_D=-7A,$ $V_{DS}=-10V$ $V_{GS}=-4.5V$	--	46	---	nC
Gate-to-Source Charge	Q_{gs}		--	8.7	--	
Gate-to-Drain Charge	Q_{gd}		--	10.6	---	
Turn-On Delay Time	$T_d(on)$	$V_{DD}=10V,$ $I_D=-7A,$ $R_g=2.2\Omega,$ $V_{GS}=-10V$	--	8.5	--	nS
Turn-On Rise Time	T_r		--	65	--	
Turn-Off Delay Time	$T_d(off)$		--	120	--	
Turn-Off Fall Time	T_f		--	42	--	
Continuous Diode Forward Current	I_S	--	--	--	-14	A
Pulsed Diode Forward Current	I_{SM}	--	--	--	-55	A
Diode Forward Voltage	V_{SD}	$T_J=25^\circ C, I_S=-7A$ $V_{GS}=0V$	--	--	-1.2	V
Reverse Recovery Time	t_{rr}	$I_f=I_S$ $di_F/dt=100A/\mu s$	--	16	--	ns
Reverse Recovery Charge	Q_{rr}		--	7.1	--	μC

●Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
Thermal Resistance Junction-case	R_{thJC}	3.3	°C/W
Thermal Resistance Junction-ambient ³	R_{thJA}	36	°C/W

Notes:

1. Repetitive rating; pulse width limited by max junction temperature.
2. Pulse Test : Pulse width $\leq 300 \mu s$, Duty cycle $\leq 2\%$.
3. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.

● Typical Characteristics

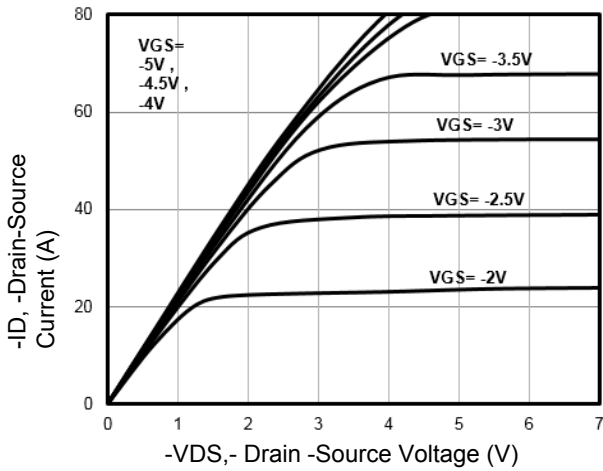


Fig1, Typical Output Characteristics

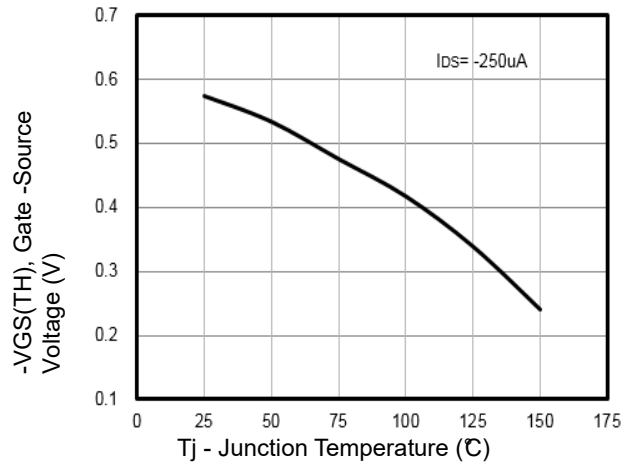


Fig2, $-V_{GS(TH)}$ Gate -Source Voltage Vs. T_j

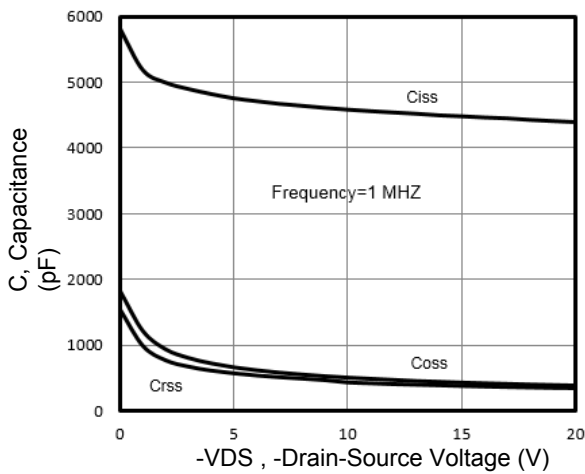


Fig3, Typical Capacitance Vs. Drain-Source Voltage

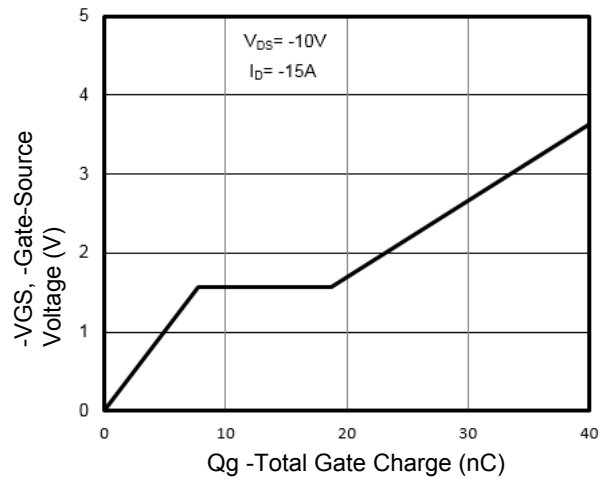


Fig4, Typical Gate Charge Vs. Gate-Source Voltage

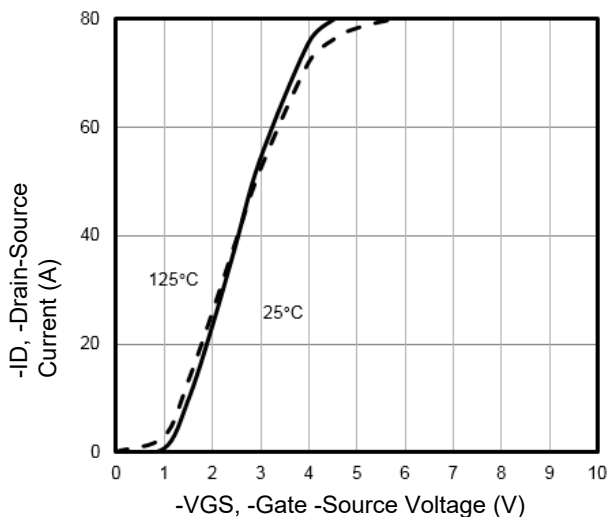


Fig5, Typical Transfer Characteristics

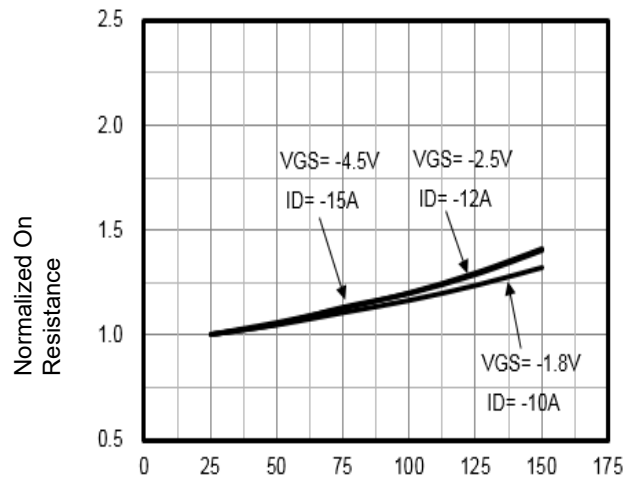


Fig6, Normalized On-Resistance Vs. T_j

● **Typical Characteristics(Cont.)**

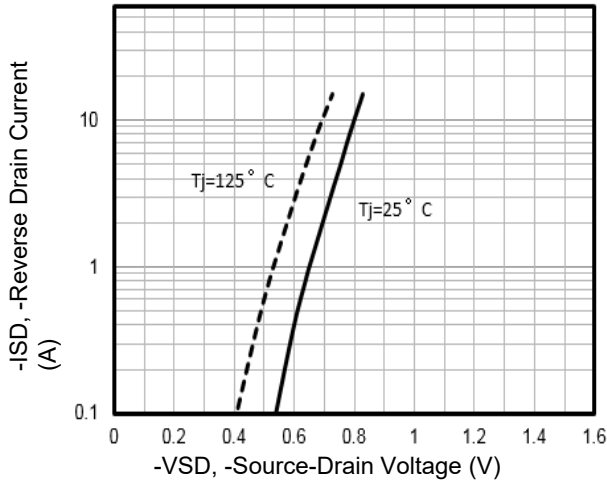


Fig7, Typical Source-Drain Diode Forward Voltage

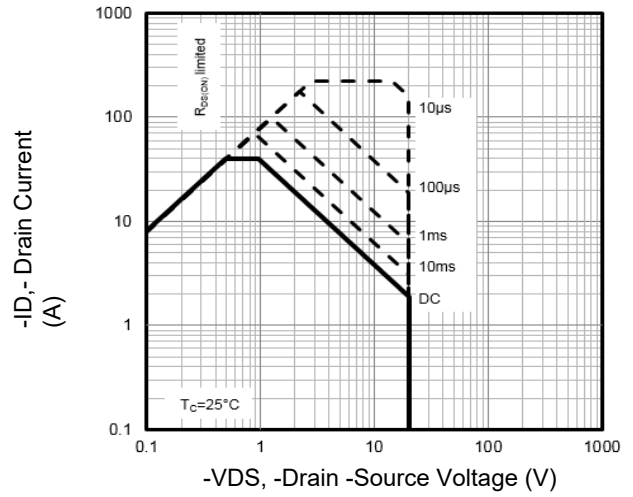


Fig8, Maximum Safe Operating Area

● **Test Circuit & Waveforms**

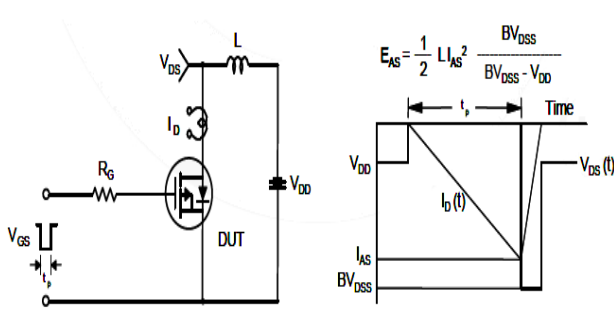


Fig1. Unclamped Inductive Test Circuit and Waveforms

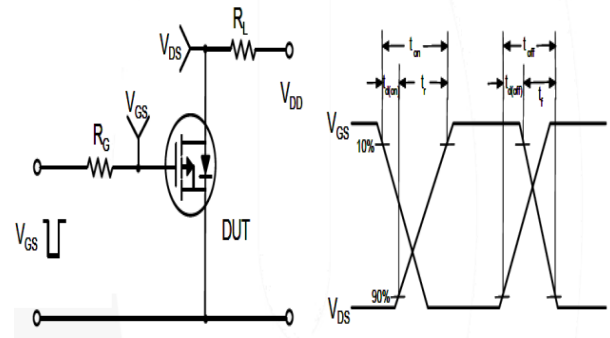


Fig2. Switching Time Test Circuit and waveforms

●Dimensions (SOP-8)

UNIT:mm

SYMBOL	min	max	SYMBOL	min	max
A	1.30	1.60	e	1.27BSC	
A1	1.35	1.85	L	0.40	1.30
b	0.30	0.60			
C	0.15	0.35			
D	4.60	5.20			
E	3.70	4.10			
E1	5.70	6.30			

